

### TOSHIBA THYRISTOR SILICON PLANAR TYPE

# **USF05G49**

# LOW POWER SWITCHING AND CONTROL APPLICATIONS

 Repetitive Peak Off-State Voltage : VDRM = 400 V Repetitive Peak Reverse Voltage : VRRM = 400 V
 Average On-State Current : IT (AV) = 500 mA

### **MAXIMUM RATINGS**

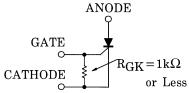
CHARACTERISTIC	SYMBOL	RATING	UNIT	
Repetitive Peak Off-State Voltage and Repetitive Peak Reverse Voltage	V <sub>DRM</sub> V <sub>RRM</sub>	400	V	
Non-Repetitive Peak Reverse Voltage (Non-Repetitive<5ms, $T_j = 0\sim125^{\circ}C$ )	V <sub>RSM</sub>	500	V	
Average On-State Current (Half Sine Waveform)	I <sub>T (AV)</sub>	500	mA	
R.M.S On-State Current	I <sub>T (RMS)</sub>	800	mA	
Peak One Cycle Surge On-State Current (Non-Repetitive)	I <sub>TSM</sub>	9 (50Hz)	А	
		10 (60Hz)		
I <sup>2</sup> t Limit Value	I <sup>2</sup> t	0.4	A <sup>2</sup> s	
Critical Rate of Rise of On-State Current (Note 1)	di / dt	10	A/ <sub>µs</sub>	
Peak Gate Power Dissipation	P <sub>GM</sub>	0.1	W	
Average Gate Power Dissipation	P <sub>G(AV)</sub>	0.01	W	
Peak Forward Gate Voltage	$V_{FGM}$	3.5	V	
Peak Reverse Gate Voltage	$V_{RGM}$	-5	V	
Peak Forward Gate Current	I <sub>GM</sub>	125	mA	
Junction Temperature	Tj	-40~125	°C	
Storage Temperature Range	T <sub>stg</sub>	-40~125	°C	

Note 1: di / dt Test condition:  $i_G = 5mA$ ,  $t_{gw} = 10\mu s$ ,  $t_{gr} \le 250ns$ 

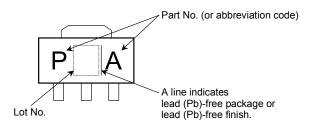
### Unit: mm 1.6MAX. 4.6MAX 1.7MAX. 0.4 ± 0.05 4.2MAX +0.08 0.45 - 0.05 +0.08 0.4 - 0.05 $1.5 \pm 0.1$ 1.5 ± 0.1 1. GATE ANODE CATHODE **JEDEC** JEITA **TOSHIBA** 13-5B1A

Weight: 0.2 g (typ.)

Note: Should be used with gate resistance as shown below.



### **MARKING**

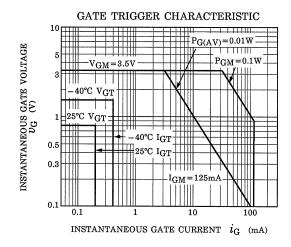


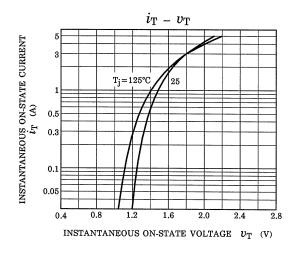
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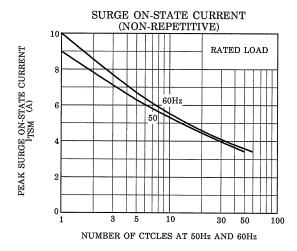
## ELECTRICAL CHARACTERISTICS (Ta = 25°C)

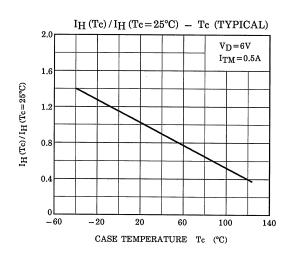
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Repetitive Peak Off-State Current and Repetitive Peak Reverse Current	I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>DRM</sub> = V <sub>RRM</sub> = Rated	_	_	10	μA
Peak On-State Voltage	V <sub>TM</sub>	I <sub>TM</sub> = 1A	_	_	1.5	V
Gate Trigger Voltage	V <sub>GT</sub>	$V_D = 6V, R_L = 100\Omega$	_	_	0.8	V
Gate Trigger Current	I <sub>GT</sub>	$R_{GK} = 1k\Omega$	I	ı	200	μA
Holding Current	lΗ	$I_{TM}$ = 500mA, $V_D$ = 6V $R_{GK}$ = 1k $\Omega$	ı	ı	6	mA
Critical Rate of Rise of Off-State Voltage	d <sub>V</sub> / dt	$V_{DRM}$ = Rated, $R_{GK}$ = 1kΩ Exponential Rise	-	200	_	V / µs
Gate Turn-On Time	t <sub>gt</sub>	$V_D$ = Rated, $i_G$ = 5mA R <sub>GK</sub> = 1k $\Omega$	l		1.5	μs
Thermal Resistance	R <sub>th(j−a)</sub>	Junction to Ambient		_	70	°C/W

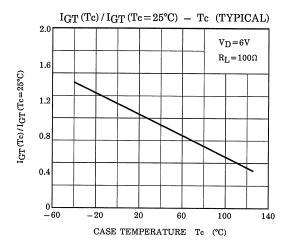
Note: Thermal Resistance Test Condition Use 0.6×30×30mm Alumina Plate

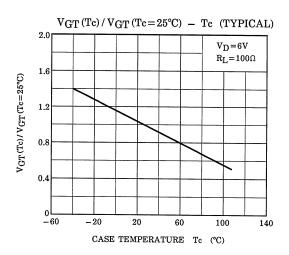


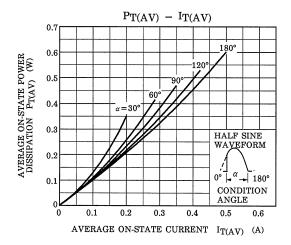


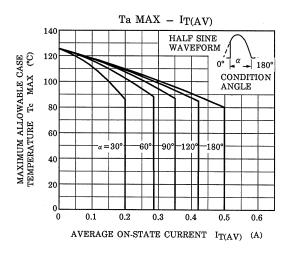


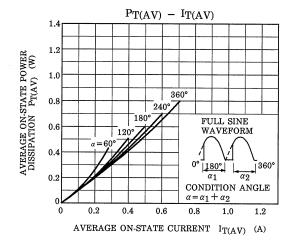


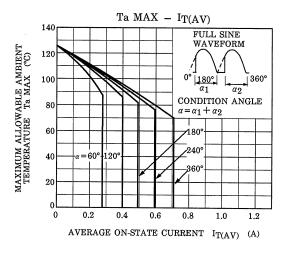


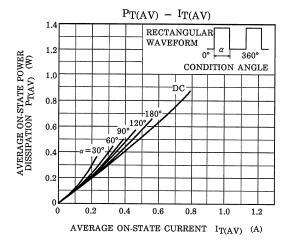


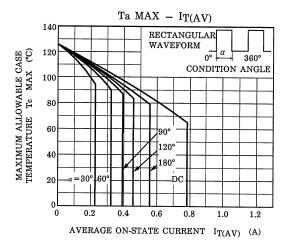


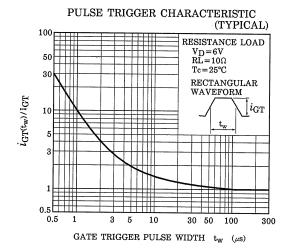


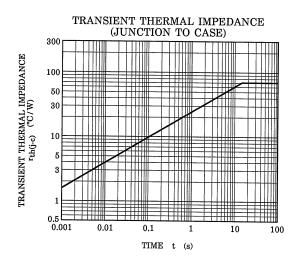












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